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FDS6982S

Dual Notebook Power Supply N-Channel PowerTrench® SyncFet[™]

General Description

The FDS6982S is designed to replace two single SO-8 MOSFETs and Schottky diode in synchronous DC:DC power supplies that provide various peripheral voltages for notebook computers and other battery powered electronic devices. FDS6982S contains two unique 30V, N-channel, logic level, PowerTrench MOSFETs designed to maximize power conversion efficiency.

The high-side switch (Q1) is designed with specific emphasis on reducing switching losses while the low-side switch (Q2) is optimized to reduce conduction losses. Q2 also includes an integrated Schottky diode using Fairchild's monolithic SyncFET technology.

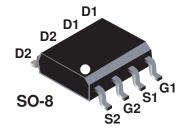
Features

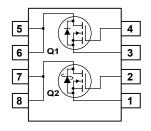
 Q2: Optimized to minimize conduction losses Includes SyncFET Schottky body diode

8.6A, 30V
$$R_{DS(on)} = 0.016\Omega$$
 @ $V_{GS} = 10V$ $R_{DS(on)} = 0.022\Omega$ @ $V_{GS} = 4.5V$

Q1: Optimized for low switching losses
Low Gate Charge (8.5 nC typical)

6.3A, 30V
$$R_{DS(on)} = 0.028\Omega$$
 @ $V_{GS} = 10V$ $R_{DS(on)} = 0.035\Omega$ @ $V_{GS} = 4.5V$





Absolute Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter		Q2	Q1	Units
V _{DSS}	Drain-Source Voltage		30	30	V
V _{GSS}	Gate-Source Voltage		±20	±20	V
I _D	Drain Current - Continuous	(Note 1a)	8.6	6.3	Α
	- Pulsed		30	20	
P _D	Power Dissipation for Dual Operation		2	W	
	Power Dissipation for Single Operation	(Note 1a)	1.0	6	
		(Note 1b)	1		
		(Note 1c)	0.9	9	
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to	+150	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	78	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	(Note 1)	40	°C/W

Package Marking and Ordering Information

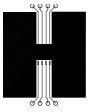
Device Marking Device		Reel Size	Tape width	Quantity
FDS6982S	FDS6982S FDS6982S 13		12mm	2500 units

Symbol	Parameter	Test Conditions	Type	Min	Тур	Max	Units
Off Cha	racteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$ $V_{GS} = 0 \text{ V}, I_D = 250 \text{ uA}$	Q2 Q1	30 30			V
<u>ΔBV_{DSS}</u> ΔT _J	Breakdown Voltage Temperature Coefficient	I _D = 1 mA, Referenced to 25°C I _D = 250 μA, Referenced to 25°C	Q2 Q1		20 26		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 24 V, V _{GS} = 0 V	Q2 Q1			500 1	μА
I _{GSSF}	Gate-Body Leakage, Forward	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$	All			100	nA
I_{GSSR}	Gate-Body Leakage, Reverse	V _{GS} = -20 V, V _{DS} = 0 V	All			-100	nA
On Chai	racteristics (Note 2)						
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 1 \text{ mA}$ $V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	Q2 Q1	1		3 3	V
$\Delta V_{GS(th)} \over \Delta T_J$	Gate Threshold Voltage Temperature Coefficient	I_D = 1 mA, Referenced to 25°C I_D = 250 μ A, Referenced to 25°C	Q2 Q1		-3.5 -5		mV/°C
R _{DS(on)}	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}, I_D = 8.6 \text{ A}$ $V_{GS} = 10 \text{ V}, I_D = 8.6 \text{ A}, T_J = 125^{\circ}\text{C}$ $V_{GS} = 4.5 \text{ V}, I_D = 7.5 \text{ A}$ $V_{GS} = 10 \text{ V}, I_D = 6.3 \text{ A}$ $V_{GS} = 10 \text{ V}, I_D = 6.3 \text{ A}, T_J = 125^{\circ}\text{C}$ $V_{GS} = 4.5 \text{ V}, I_D = 5.6 \text{ A}$	Q2 Q1		0.013 0.020 0.017 0.021 0.038 0.028	0.016 0.027 0.022 0.028 0.047 0.035	Ω
I _{D(on)}	On-State Drain Current	V _{GS} = 10 V, V _{DS} = 5 V	Q2 Q1	30 20			Α
g FS	Forward Transconductance	$V_{DS} = 5 \text{ V}, I_{D} = 8.6 \text{ A}$ $V_{DS} = 5 \text{ V}, I_{D} = 6.3 \text{ A}$	Q2 Q1		38 18		S
Dynami	c Characteristics						
C _{iss}	Input Capacitance	$V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz	Q2 Q1		2040 815		pF
C _{oss}	Output Capacitance		Q2 Q1		615 186		pF
C _{rss}	Reverse Transfer Capacitance		Q2 Q1		216 66		pF

Symbol	Parameter	Test Condition	ons	Туре	Min	Тур	Max	Units
Switchir	ng Characteristics (Note	2)						
$t_{d(on)}$	Turn-On Delay Time	$V_{DD} = 15 \text{ V}, I_{D} = 1 \text{ A},$ $V_{GS} = 10 \text{ V}, R_{GEN} = 6 \Omega$		Q2 Q1		10 10	18 18	ns
t _r	Turn-On Rise Time			Q2 Q1		10 14	18 25	ns
$t_{\text{d(off)}}$	Turn-Off Delay Time			Q2 Q1		34 21	55 34	ns
t _f	Turn-Off Fall Time			Q2 Q1		14 7	23 14	ns
Qg	Total Gate Charge	Q2 V _{DS} = 15 V, I _D = 11.5 A,	V _{GS} = 5 V	Q2 Q1		17.5 8.5	25 12	nC
Q _{gs}	Gate-Source Charge	Q1		Q2 Q1		6.3 2.4		nC
Q_{gd}	Gate-Drain Charge	V_{DS} = 15 V, I_{D} = 6.3 A, V	_{GS} = 5 V	Q2 Q1		5.4 3.1		nC
Drain-S	ource Diode Character	istics and Maximur	n Ratings	,				•
Is	Maximum Continuous Drain-Source Diode Forward Current			Q2 Q1			3.0 1.3	Α
t _{RR}	Reverse Recovery Time	I _F = 11.5A,		Q2		20		ns
Q _{RR}	Reverse Recovery Charge	$d_{iF}/d_{t} = 300 \text{ A/}\mu\text{s}$	(Note 3)			19.7		nC
V_{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 3 \text{ A}$ $V_{GS} = 0 \text{ V}, I_S = 6 \text{ A}$ $V_{GS} = 0 \text{ V}, I_S = 1.3 \text{ A}$	(Note 2) (Note 2) (Note 2)	Q2 Q2 Q1		0.42 0.56 0.70	.7 1.2	V

Notes

 R_{8JA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{8JC} is guaranteed by design while R_{8CA} is determined by the user's board design.



a) 78°/W when mounted on a 0.5 in² pad of 2 oz copper



b) 125°/W when mounted on a .02 in² pad of 2 oz copper

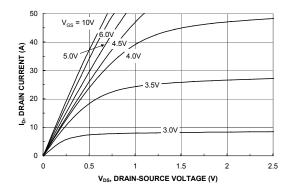


c) 135°/W when mounted on a minimum pad.

Scale 1:1 on letter size paper

- 2. Pulse Test: Pulse Width < 300μs, Duty Cycle < 2.0%
- 3. See "SyncFET Schottky body diode characteristics" below.

Typical Characteristics: Q2

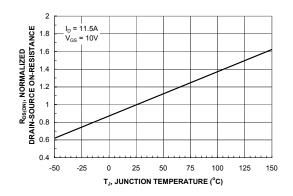


0.5 0 10 20 30 40 50

2.5

Figure 1. On-Region Characteristics.

Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.



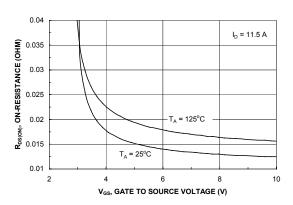
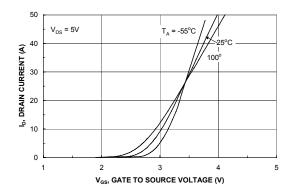


Figure 3. On-Resistance Variation with Temperature.

Figure 4. On-Resistance Variation with Gate-to-Source Voltage.



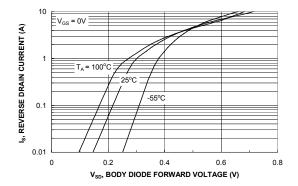
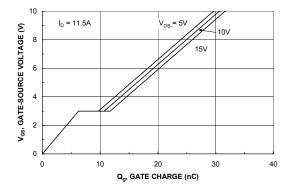


Figure 5. Transfer Characteristics.

Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics: Q2



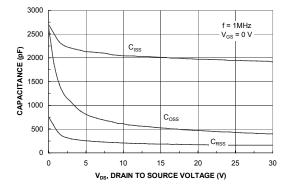
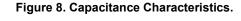
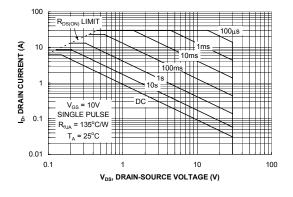


Figure 7. Gate Charge Characteristics.





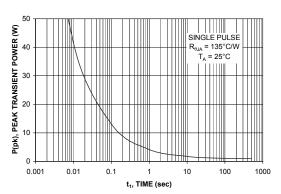


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

Typical Characteristics Q1

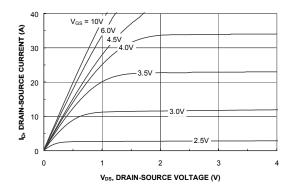
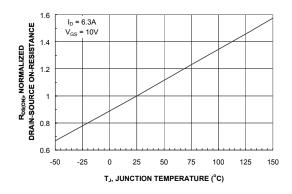


Figure 11. On-Region Characteristics.

Figure 12. On-Resistance Variation with Drain Current and Gate Voltage.



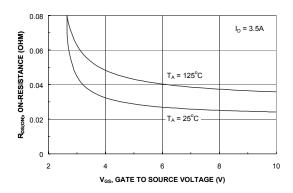
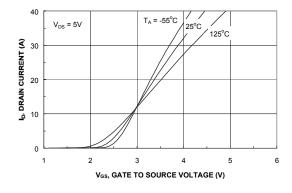


Figure 13. On-Resistance Variation with Temperature.

Figure 14. On-Resistance Variation with Gate-to-Source Voltage.



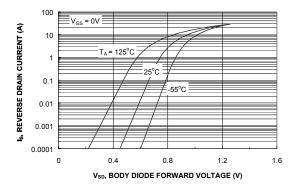
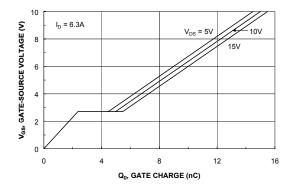


Figure 15. Transfer Characteristics.

Figure 16. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics Q1



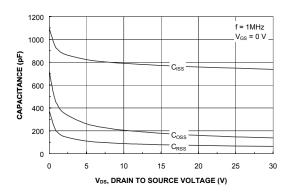


Figure 17. Gate Charge Characteristics.

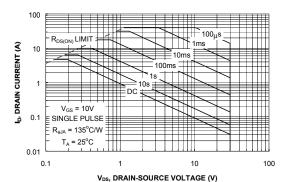


Figure 18. Capacitance Characteristics.

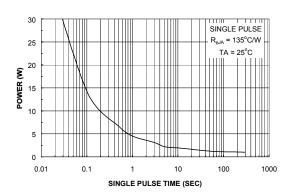


Figure 19. Maximum Safe Operating Area.



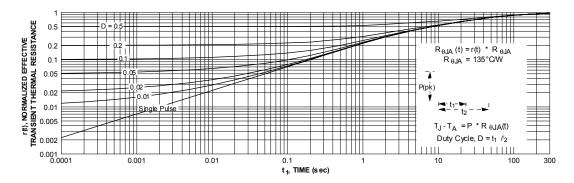


Figure 21. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient thermal response will change depending on the circuit board design.

Typical Characteristics (continued)

SyncFET Schottky Body Diode Characteristics

Fairchild's SyncFET process embeds a Schottky diode in parallel with PowerTrench MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 12 shows the reverse recovery characteristic of the FDS6982S.

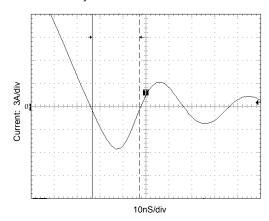


Figure 12. FDS6982S SyncFET body diode reverse recovery characteristic.

For comparison purposes, Figure 13 shows the reverse recovery characteristics of the body diode of an equivalent size MOSFET produced without SyncFET (FDS6982).

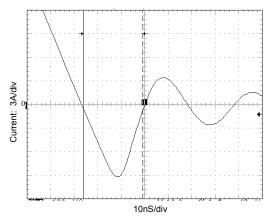


Figure 13. Non-SyncFET (FDS6982) body diode reverse recovery characteristic.

Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

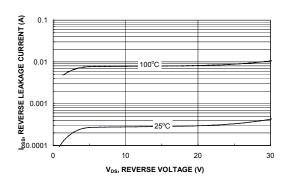


Figure 14. SyncFET body diode reverse leakage versus drain-source voltage and temperature.

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